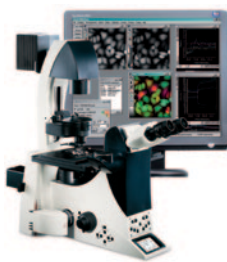


## IndustryNews

**L.A.B.** – the European trade fair and conference for analysis, bio and laboratory equipment in the UK announces that the United Kingdom Science Park Association (UKSPA) will be supporting L.A.B. 2009 in Birmingham. Staged every two years, L.A.B. will be held at the National Exhibition Centre (NEC) in Birmingham from October 27-29, 2009 and is the only platform of its kind in the UK for the European laboratory and analysis sector. UKSPA will be supporting L.A.B. by organizing conference streams focusing on current issues and best practice for laboratories including those based on UK Science Parks. For more details of the event and UKSPA's contributions visit [www.ukspa.org.uk/lab2009](http://www.ukspa.org.uk/lab2009)

### Leica Microsystems and MDS Analytical Technologies

today announced the launch of Leica MM AF imaging systems, a product line that combines Leica's industry-leading microscopy and MDS Analytical Technologies' latest MetaMorph® software. The new product line offers tightly integrated systems based on the excellent ease-of-use and optical performance of the Leica microscope range, giving researchers an efficient platform for many types of imaging experiments. An integrated journaling capability is included that allows flexible customization of the platform for virtually any imaging application. Leica MM AF imaging systems will be distributed, marketed, and fully supported through Leica Microsystems' worldwide distribution and support network. For more information, please contact: Leica Microsystems: Dr. Kirstin Henze, [kirstin.henze@leica-microsystems.com](mailto:kirstin.henze@leica-microsystems.com)



**The Leica FS M** comparison microscope is a universal instrument for high-precision firearm and toolmark examinations. The versatile system can be configured with dual viewing accessories for the simultaneous observation of evidence. The highly stable comparison bridge supports two precisely matched sets of apochromatically-corrected objectives on the five-position, ball-bearing nosepieces. The bridge is opto-mechanically designed to provide a variety of different views: split image, full left, and full right, as well as superimposed imaging of the specimens on each microscope stage. The system's excellent stability and superior optics provide a 22mm field of view with erect, unreversed images. The parfocal and parcentric objectives allow quick examination of specimens in discrete magnifications from 4x to 160x without refocusing. For more information see: [www.leica-microsystems.com](http://www.leica-microsystems.com)



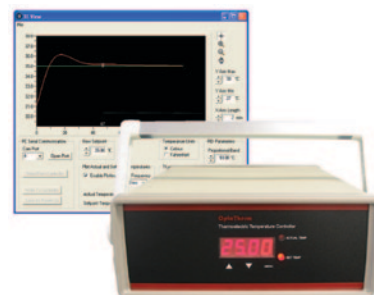
**JEOL USA and the College of Microscopy**, the education division of The McCrone Group, are proud to announce that JEOL USA will provide a new JSM-6610LV low vacuum high-performance Scanning Electron Microscope (SEM) to the College of Microscopy



for use in basic and advanced training in electron microscopy. Additionally, a JEOL staff scientist will teach existing SEM courses at the College of Microscopy, help develop specialized classes specifically utilizing the JSM-6610LV and work with McCrone scientists to develop new applications for six JEOL instruments already onsite. The College will now incorporate its JEOL JSM-6610LV into existing scanning electron courses, offering students from a wide variety of fields state-of-the-art instrumentation to improve their understanding of particle analysis. Visit [www.jeolusa.com](http://www.jeolusa.com), or call 978-535-5900.

### The OptoTherm HP20

provides precise temperature control ( $\pm 0.01^\circ\text{C}$ ) of thermoelectric modules and heating/cooling stages within a temperature range of  $-40$  to  $250^\circ\text{C}$ . The HP20 operates in a bi-directional, H-bridge configuration for smooth transitions between heating and cooling cycles and provides output current of up to 20 amps at 12 VDC. The HP20's PID capabilities enable rapid response to changes in operating conditions and provide tight control over a broad temperature range. TE View, the included PC-based software, provides an intuitive interface for configuring and operating the controller via the controller's serial (RS-232) interface. When the controller is connected to a PC, the setpoint and actual temperatures can be plotted in real time and imported into data analysis programs. Contact info: Website: [www.optotherm.com](http://www.optotherm.com).



### The new state-of-the-art 32 megapixel digital microscope camera, the PAXcamARC+

uses a state-of-the-art CCD imager, which is capable of very low light imaging - combined with "PixelShift"™ technology, the camera produces images with adjustable resolution (to users preference) all the way up to 32MP - which is a BMP format image over 100MB in file size. Contact: Gregg Kleinberg - VP New Business Development, MIS Inc. [greggk@paxit.com](mailto:greggk@paxit.com), [www.paxit.com](http://www.paxit.com)



'**ICX285**' sensor from Sony® and is engineered to deliver the highest sensitivity and dynamic range performance available from high-resolution scientific interline CCD cameras. Andor's proven vacuum process, alongside close attention to thermal management, has resulted in deep air cooling to  $-45^\circ\text{C}$  for elimination of darkcurrent, complementing a uniquely low read noise floor of  $3e^-$  rms. Dynamic events can be followed with outstanding quantitative stability via low noise 10 or 20 MHz readout modes, the data channeled through a trouble-free USB 2.0 interface. The compact, robust design and accessible SDK, renders Clara ideally suited to OEM integration. For more information, please visit [www.andor.com/scientific\\_cameras/clara/Andor](http://www.andor.com/scientific_cameras/clara/Andor)

**e2v** today announced the launch of the DiViiNA line scan camera family, their new cost effective industrial inspection camera that features the proven quality of 1024, 2048 and 4096 pixel sensors

from e2v, running at 40 MHz and outputting 8 bits on Camera Link. The DiViiNA cameras are easy-to-use and robust, with user friendly levels of functionality providing the perfect image quality for mid-range applications. They have been specifically designed for machine vision system integrators looking for cost effective solutions for mid-range applications, but who remain eager to maintain high end CCD performance. DiViiNA is already available for evaluation, with initial production units scheduled for availability by April 2009. Further information is available from [www.e2v.com](http://www.e2v.com)

**The LSM 700 Laser Scanning Microscope** from Carl Zeiss at an extremely attractive price/performance ratio. The LSM 700's The system can be combined with a large number of microscope stands and tailored to the personal requirements of each user. The ZEN 2009 software from Carl Zeiss makes its operation very clear and easy to learn allowing intuitive use even by first-time users. The optical design of the LSM 700 guarantees high efficiency in the detection even of weak fluorescence signals. Key elements of the optical system include the beam path design with its maximum optical precision, the beam combiner system for accurate beam coupling and superimposition, the beam splitter with continuous and loss-free splitting of the light spectrum and the extremely stable pinhole. Please visit [www.zeiss.com/micro](http://www.zeiss.com/micro).

**Wetzlar, Germany.** For the first time in its history, Leica Microsystems' annual sales volume for 2008 exceeded the billion US dollar mark, reports the international high-tech microscope and scientific instrument manufacturer and distributor, headquartered in Wetzlar. "Over the last two years, we have seen a dramatic increase in the demand for our products throughout the world. In most of the markets in which we operate – including biomedical research, clinical applications, industry, microsurgery, and histopathology – we have achieved double-digit organic growth rates. Moreover, we have substantially expanded our product breadth through a number of strategic company acquisitions," comments Dr. David Martyr, President of Leica Microsystems.

**SEMTECH SOLUTIONS ANALYTICAL TESTING LABORATORY** announces the launch of its new website. The site can be found at [www.atl.semtechsolutions.com](http://www.atl.semtechsolutions.com). This new website provides users with images and descriptions of Scanning Electron Microscopy (SEM) techniques for various materials. Also included is information about SEMTECH Solution's services, capabilities, and equipment. Visitors to the site will be able to access on-line instructions and forms to submit samples for testing and analysis. Our Microscopy Lab is an unbiased resource, providing confidential research and developmental support for materials testing, identification, technical problem solving, and analysis. Our laboratory includes a Field Emission Scanning Electron Microscope (FE-SEM), a unique 3D FE-SEM for surface roughness analysis, a Polarizing Light Microscope (PLM), and several stereo optical microscopes. Visit [www.atl.semtechsolutions.com](http://www.atl.semtechsolutions.com).

**Asylum Research**, announced a new Atomic Force Microscopy (AFM) new CoolerHeater accessory designed for polymer and other studies where cooling and heating are required for the MFP-3D AFM platform. The CoolerHeater uses a Peltier element to both cool samples down to  $-35^{\circ}\text{C}$  and heat up to  $+120^{\circ}\text{C}$ . The heating or cooling temperature and heating rate are easily and conveniently set using the AFM software and computer-controlled. The CoolerHeater can be sealed for use in air or in a controlled gaseous environment.

This new product complements the MFP-3D PolyHeater™, a modular heating stage designed specifically for high-temperature studies from ambient to  $300^{\circ}\text{C}$  in a controlled gaseous environment. See 'Products' at [www.asylumresearch.com](http://www.asylumresearch.com) with links to data sheets on the individual products.

**Scientists at Florida State University (FSU)** will finally be able to clearly see each individual atom and how it relates to its neighbors when they take delivery of a new JEOL atomic resolution Scanning Transmission Electron Microscope (S/TEM) later this year at FSU's Applied Superconductivity Center, housed in the National High Magnetic Field Laboratory, the High Performance Materials Institute in Tallahassee, Florida. Scientists at FSU throughout Florida, will soon have access to the highest resolution – 80 picometers, of any commercially available S/TEM in its class. The imaging and analytical resolution of the new JEOL 200kV S/TEM will make it possible to directly observe atomic position, chemical composition, and electronic bonding information that is crucial to development of novel materials with the highest performance.

**JEOL USA**, announced the promotion of Peter Genovese to the position of President. Mr. Genovese, a member of the JEOL sales organization for more than 25 years, most recently served as Vice President and General Manager of the Sales and Marketing Division of the company. He holds a B.S. in Economics from Boston College and an Executive M.B.A. from Suffolk University. JEOL USA employs over 300 people throughout the United States. Incorporated in 1962, it is a wholly-owned subsidiary of JEOL, Ltd., with headquarters in Akishima, Japan. Mr. Genovese's new position was announced at the company's annual meeting by Mr. Robert Santorelli, CEO of JEOL USA.

**Nikon Instruments, Inc.** ([www.nikoninstruments.com](http://www.nikoninstruments.com)) introduces the new MM-200 Measuring Microscope. Ideal for measuring a variety of metal, plastic and electronic parts, this powerful new microscope is specifically designed and engineered with machining engineers and inspectors in mind. The MM-200 features a space-saving footprint of just 420 x 297mm. Designed with a built-in 2" x 2" O3L type digital stage with a rotating table and digital backpack for ease of use, the MM-200 can be used with the low-cost SC2 Digital Readout. The MM-200 also features a built-on digital measuring stage, which requires no installation. The MM-200's built-in, episcopic and diascopic light sources are all long-life, high-intensity, white light LED. Inquiries may be directed to Nikon Instruments at 800-52-NIKON.



**JAI** today announced the release of two new high performance 16-megapixel cameras equipped with standard GigE Vision digital interfaces. The new GigE Vision cameras incorporate the Kodak KAI-16000 dual-tap progressive scan CCD to deliver full 4872 x 3248 pixel resolution at 3 frames per second. The AM-1600GE provides monochrome output, while the AB-1600GE produces raw Bayer color output for host-based interpolation. Both models feature user-selectable 8-bit, 10-bit, or 12-bit output. To ensure reliable performance in industrial environments, Core applications for the cameras include flat panel LCD inspection, solar panel inspection, PCB inspection, 3D metrology, biometrics, high-end security/surveillance, aerial imaging, and traffic applications.